

# Leiurus: MultiLane's Probing Solution

TDR Probing & PCB Failure Analysis

Elias Khoury

1/22/2021




# Outline

---

- Background – The Status-Quo
- Leiurus – TDR Probing Solution
  - Setup & Hardware
  - Probes
  - Key Measurements
  - Applications
- ML4035 – The Swiss Army Knife of Signal Integrity
- ML4035 Technical Specs – PPG, ED, DSO

# Background

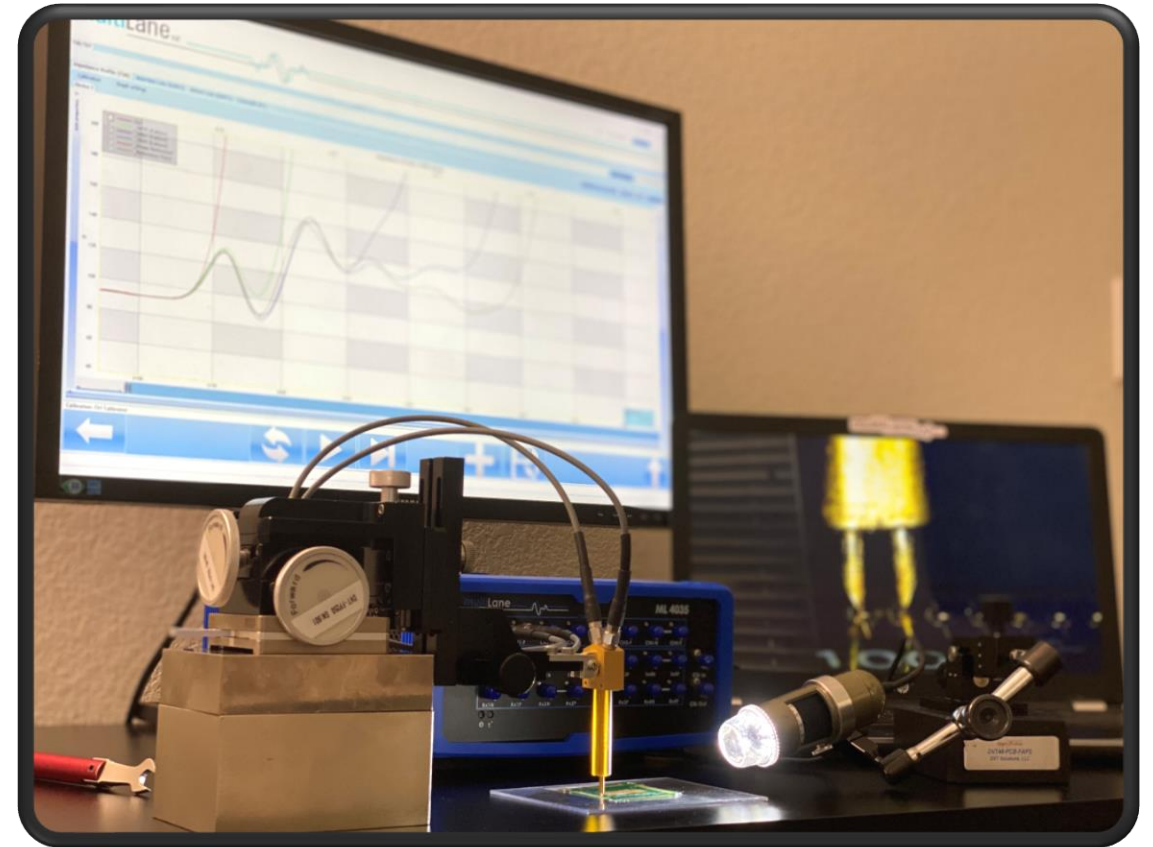
## The Status Quo

-  PCBs and connectors make up the core of high-speed systems and their reliable performance is crucial for successful operation.
-  The imbalanced growth between speed and innovative testing solutions is driving test time, complexity and cost to new heights.
-  MultiLane's goal is to provide a fast, reliable and affordable alternative to traditional testing methods, allowing PCB & connector users and manufacturers to ensure reliable operation of their products.

# Leiurus






## TDR Probing & PCB Failure Analysis

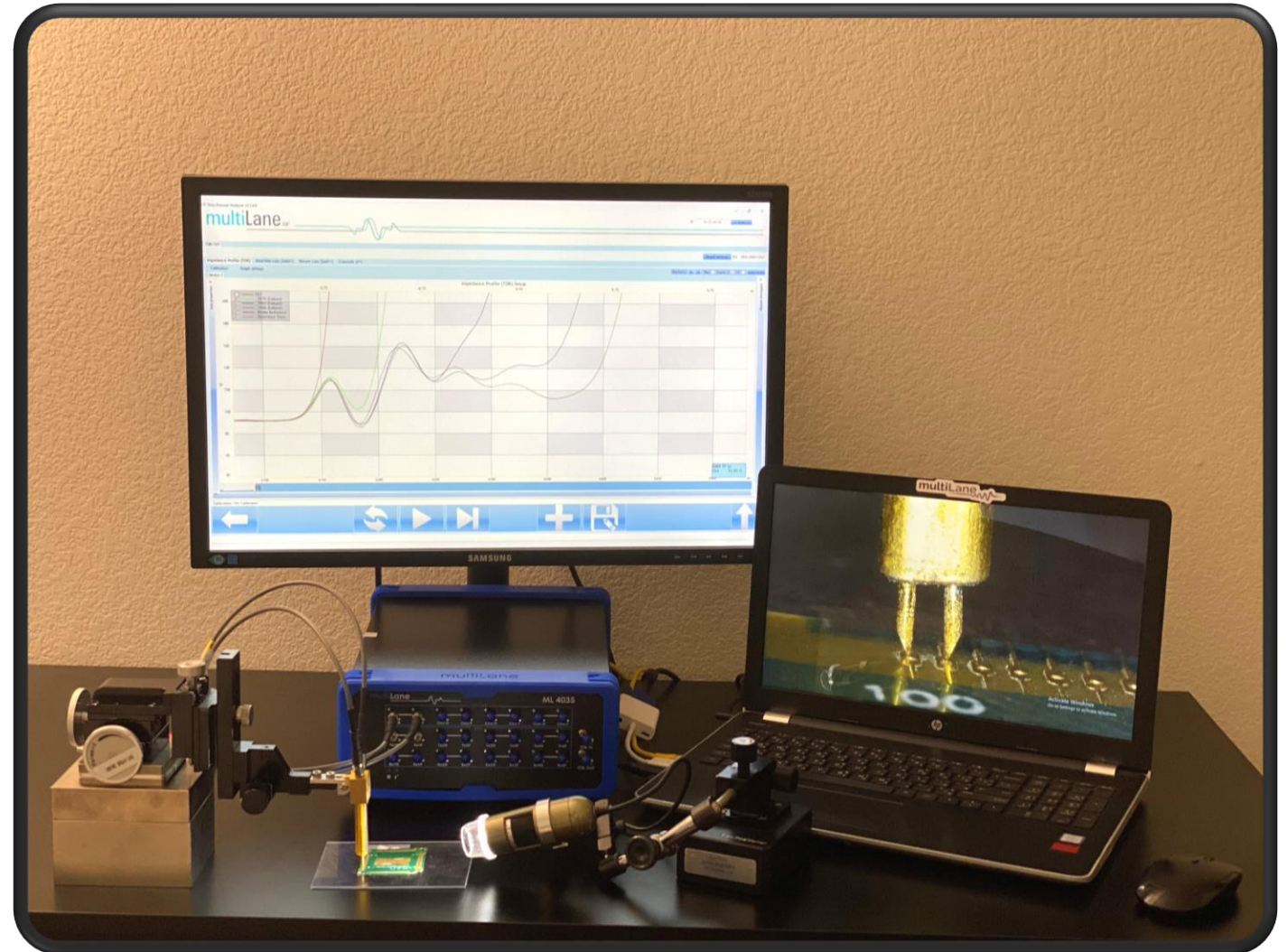
- MultiLane's solutions cover the whole spectrum of the industry's testing needs including evaluation of the smallest, most delicate, and hardest traces to reach.
- MultiLane has combined its state-of-the-art technology in its ML4035 with the high quality DVT Solutions probes to provide a comprehensive TDR probe testing solution for PCB & interconnects.



# Leiurus







## Setup & Hardware

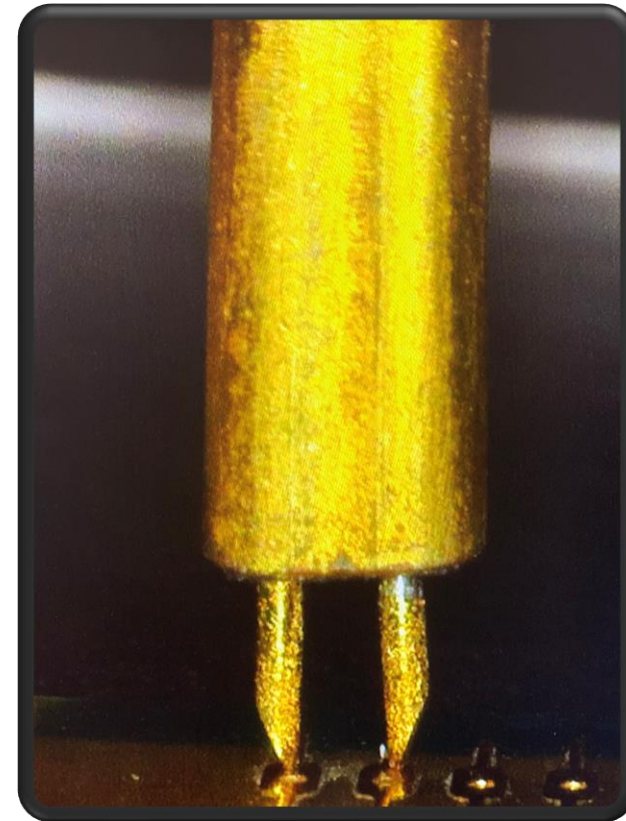
-  ML4035
-  DVT40/DVT-FP70
-  DVT-FP250 Probe Positioner
-  DVT-FP100 Magnetic Bases
-  DVT-CS1/5 Camera System



# Leiurus







## Probes

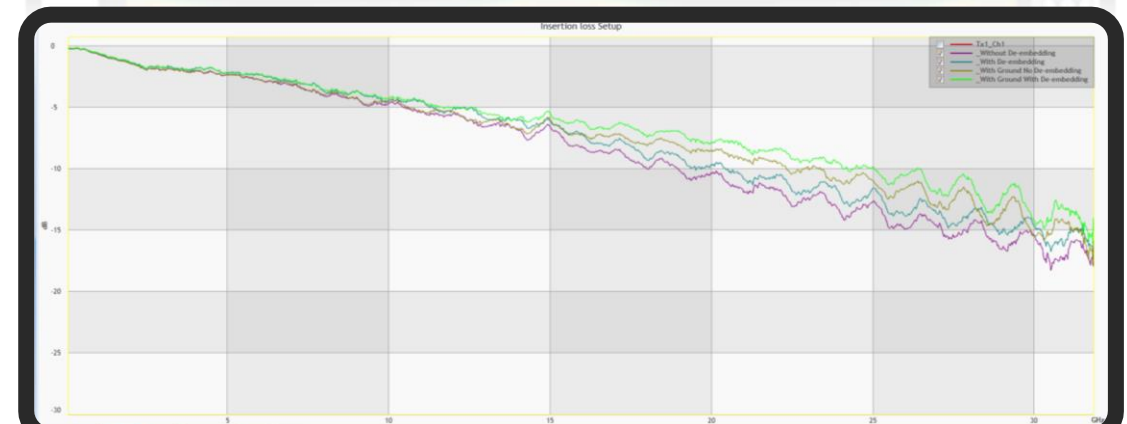
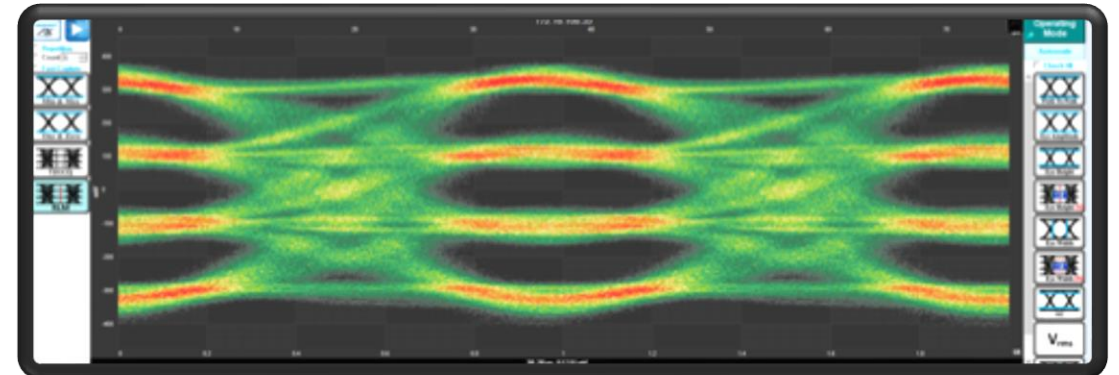
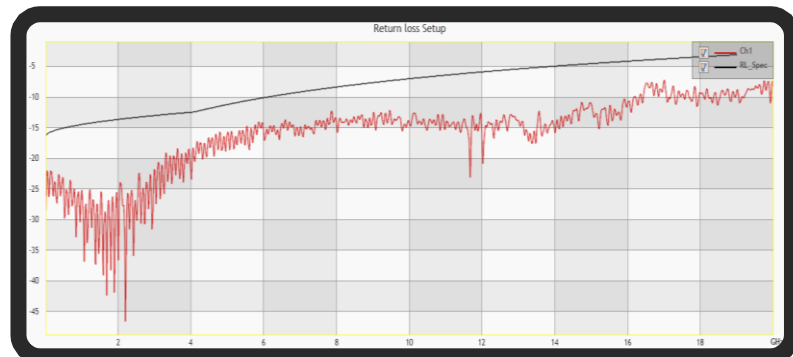
-  DVT40 (40 GHz) or DVT-FP70 (40/50/70 GHz)
-  Single-ended & true odd mode differential probes with variable pitch.
-  Conductive diamond & gold-plated probe tips
-  Can measure single-ended & differential traces that have no ground access.
-  Minimum TDR rise-time degradation
-  Repeatable TDR measurements



# Leiurus

## Key Measurements

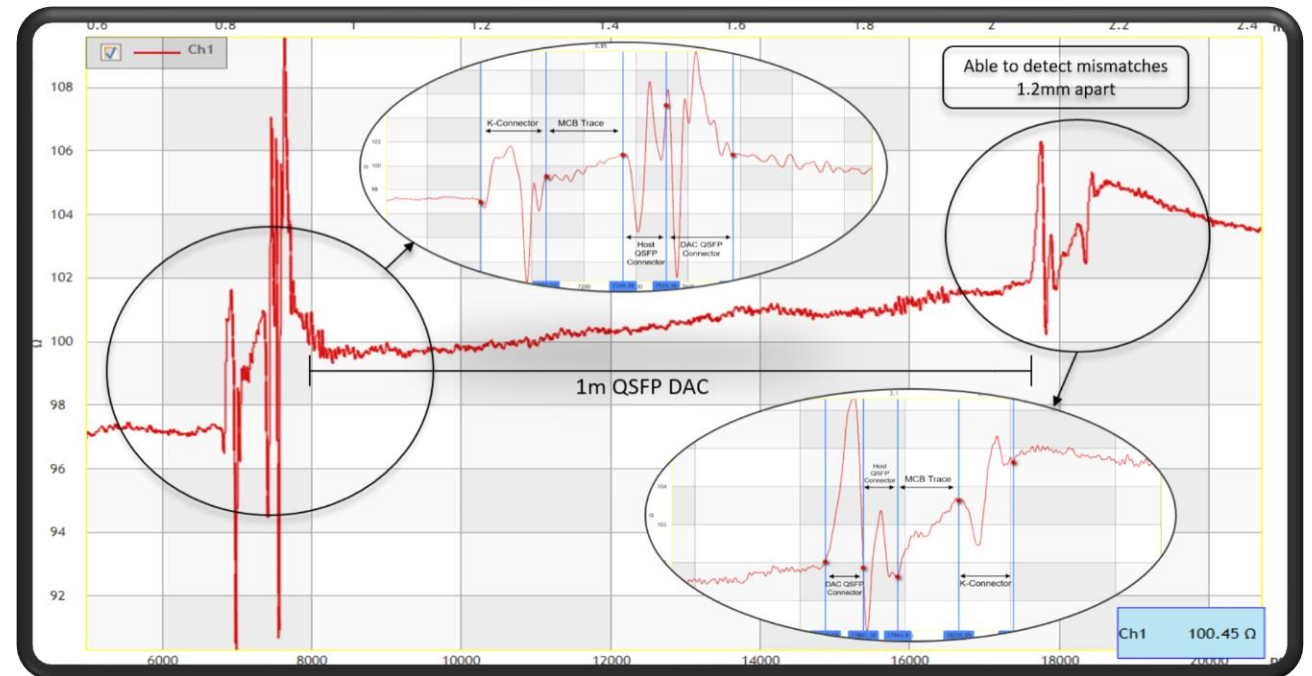
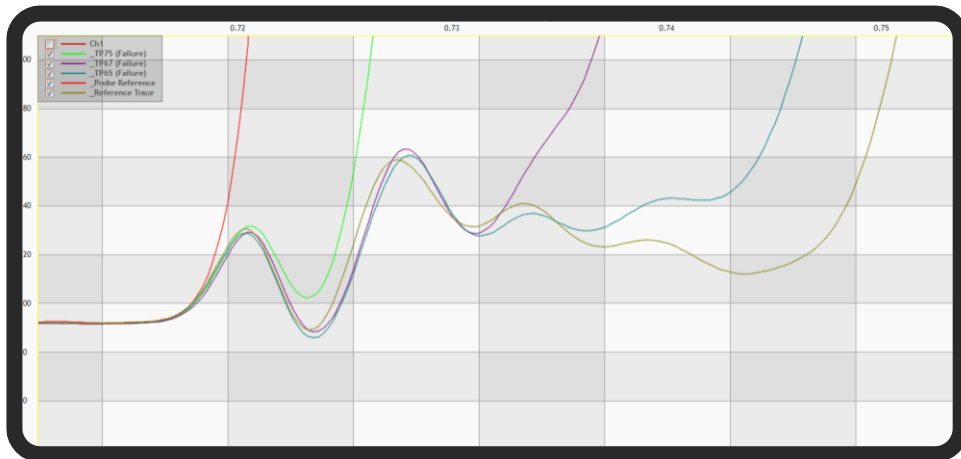
-  Impedance Profile
-  Insertion Loss
-  Return Loss
-  Crosstalk
-  Eye Diagram
-  Bit Error Rate



# Leiurus

## Applications

- Failure Analysis
- Impedance Matching
- Trace Verification
- Motherboard/daughter cards
- Chip-to-module electrical channels



# ML4035: Swiss Army Knife of SI

## Key Features








- 4-Lane Sampling Scope
- 4-Lane 53GBd PPG
- 4-Lane True-Differential TDR/TDT
- 400G Bit Error Ratio Tester
- Automation SW for DAC Testing
- High Throughput

	Port Name	Description
1	Clk In/Out	The trigger input for the sampling scope (DSO). It is used in DSO mode only.
2	CH1 - CH4	TDR/DSO ports. Each channel can be either configured as TX or RX.
3	TX1 – TX4	PPG ports. Each channel can transmit a 53GBd NRZ/PAM4 signal.
4	RX1 – RX4	Error Detector ports. Used to measure BER.
5	LAN	RJ-45 port for data transfer and communication with the GUI













# BERT Specs

## PPG Features

-  PAM-4: 22 – 29.6 and 48 – 56 GBd
-  NRZ: 22 – 29 and 48 – 56 Gbps
-  DFE Pre-coding and Gray coding
-  Channel Emulation & Full FEC
-  PRBS7/9/11/13/15/16/23/31/58  
PRBS13Q, 31Q and SSPRQ Square wave,  
JP03A/B, CID JTOL pattern
-  Maximum voltage swing: 0 – 800 mVpp
-  Pre and Post-emphasis

## ED Features

-  Total DFE/FFE/CTLE equalization up to 13 dB
-  SNR monitoring
-  FEC measurements
-  PAM4 slicer threshold adjustable
-  Reference clock output rate div 8/16/32/165
-  PRBS 7, 9, 13, 15, 23 & 31 checker
-  Automatic PRBS detection
-  Clock-data recovery
-  BER counters
-  Error insertion

# DSO Specs

## DSO Specs

- 4-Lane 35 GHz Digital Sampling Scope optimized for high-speed data analysis
- High fidelity signal capture
- Low intrinsic Jitter
- Jitter decomposition (TJ, RJ, DJ)
- CTLE, S2P De-embedding, FFE, DFE, etc...
- SSPRQ & up to PRBS16 pattern lock
- NRZ and PAM measurement Libraries (APIs)

## TDR Specs

- High resolution TDR/TDT measurements
- 4-Lane 35 GHz Time Domain Reflectometry / Transmission optimized for high-speed tests and measurements
- Impedance profile measurement
- S-Parameters:
- Return & Insertion loss
- Crosstalk
- Accurate multisport S-parameters



# THANK YOU

## Innovation for the next generation

### North America

48521 Warm Springs Boulevard  
Suite 310  
Fremont, CA 94539, USA  
+1 510 573 6388

### Worldwide

Houmal Technology Park  
Askarieh Main Road  
Houmal, Lebanon  
+961 5 941 668

### Asia

14F-5/ Rm.5, 14F., No 295  
Sec.2, Guangfu Rd. East Dist.,  
Hsinchu City 300, Taiwan (R.O.C)  
+886 3 5744 591

[www.multilaneinc.com](http://www.multilaneinc.com)